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(54) **LEAD FRAME FOR SEMICONDUCTOR DEVICE**

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H01L 23/495 (2006.01)

(52) **U.S. Cl.**

CPC . **H01L 23/49582** (2013.01); **H01L 2924/0002** (2013.01)

(58) **Field of Classification Search**

CPC H01L 23/02

USPC 257/666

See application file for complete search history.

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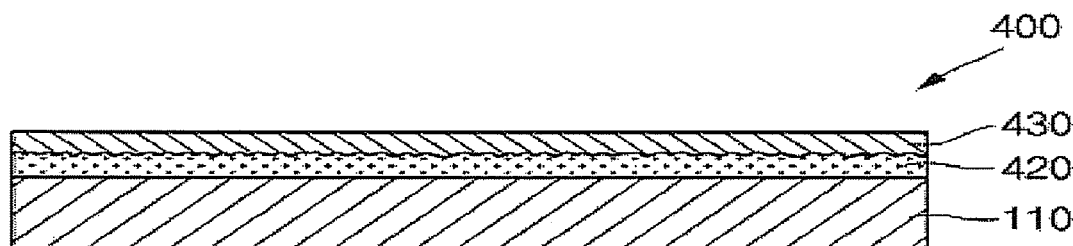
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(57) **ABSTRACT**

Provided is a lead frame for a semiconductor device, which includes a base layer made of copper, a strike plating layer or a self assembly monolayer (SAM), thereby preventing oxidation of a base layer while simplifying the manufacturing process, reducing the manufacturing costs and reducing a failure ratio. In one embodiment, in the lead frame for a semiconductor device including a die pad and a plurality of leads positioned adjacent to each other around the die pad, the lead frame includes a base layer made of copper; and a first strike plating layer formed on the one or more portions of the surface of the base layer.

15 Claims, 6 Drawing Sheets



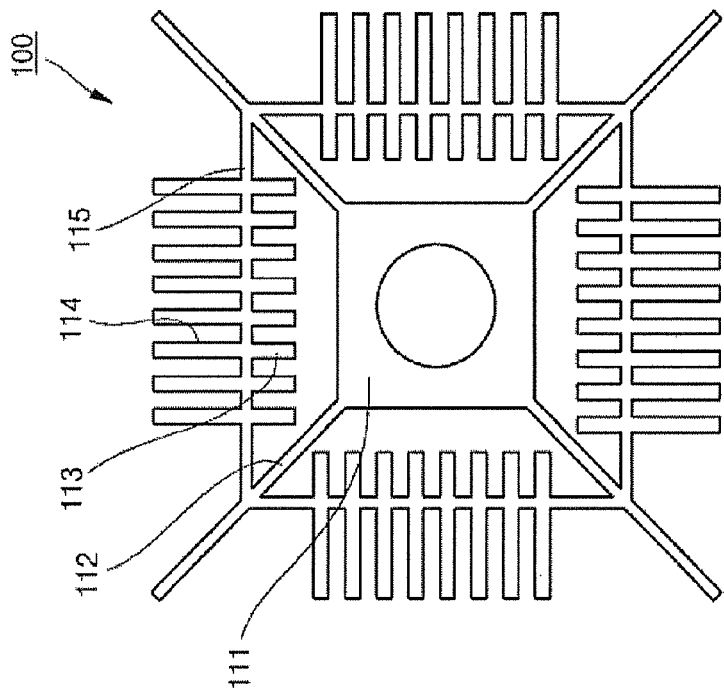


FIG. 1

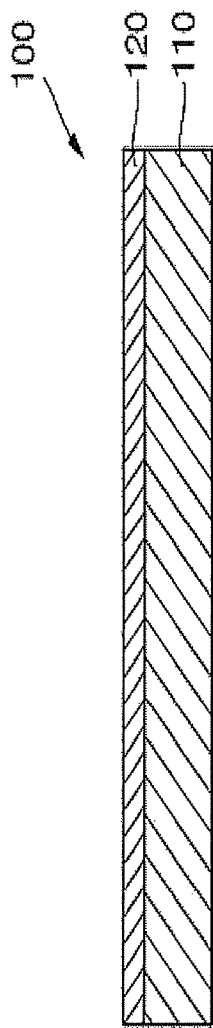


FIG. 2

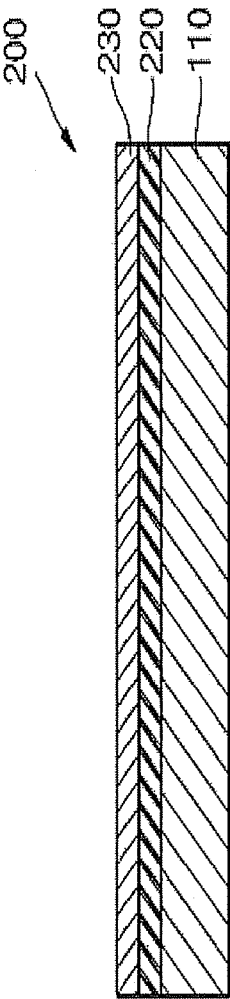


FIG. 3

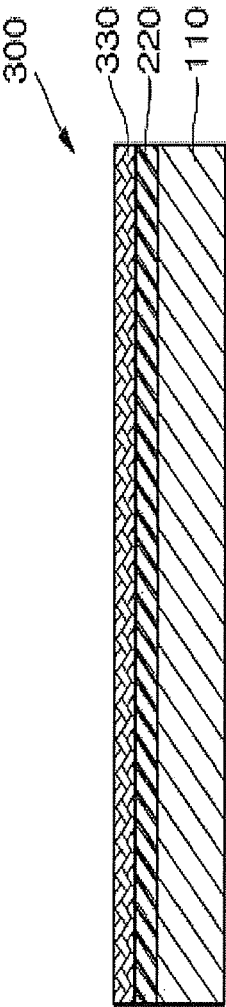


FIG. 4

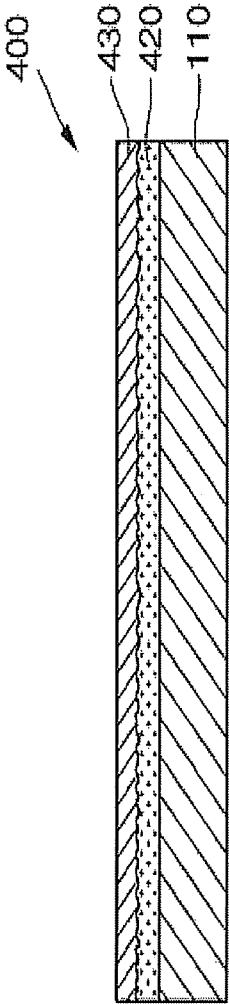


FIG. 5

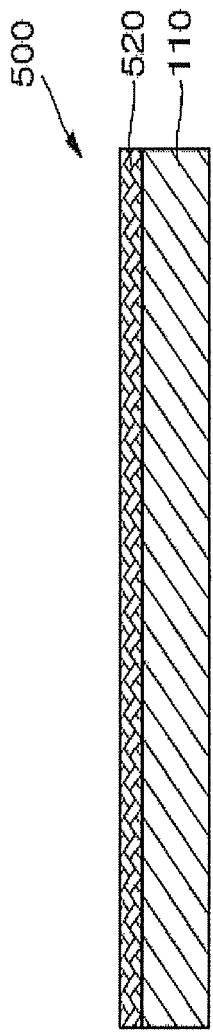


FIG. 6

LEAD FRAME FOR SEMICONDUCTOR DEVICE

CROSS-REFERENCE TO RELATED APPLICATIONS/INCORPORATION BY REFERENCE

The present application makes reference to, claims priority to, and claims the benefit of Korean Patent Application No. 10-2011-0050527, filed on May 27, 2011, the contents of which is hereby incorporated herein by reference, in its entirety.

FIELD OF THE INVENTION

The present invention relates to a lead frame for a semiconductor device.

BACKGROUND OF THE INVENTION

A lead frame for a semiconductor device is an essential component of the semiconductor device with a semiconductor die. The lead frame for a semiconductor device is manufactured by chemically etching or mechanically stamping a metal strip. The lead frame may serve as an electric lead to connect a semiconductor die to an external substrate and as a frame for fixing the semiconductor device to the external substrate.

Further limitations and disadvantages of conventional and traditional approaches will become apparent to one of skill in the art, through comparison of such systems with some aspects of the present invention as set forth in the remainder of the present application with reference to the drawings.

BRIEF SUMMARY OF THE INVENTION

A device and method is provided for a lead frame for a semiconductor device, substantially as shown in and/or described in connection with at least one of the figures, as set forth more completely in the claims.

These and other advantages, aspects and novel features of the present invention, as well as details of an illustrated embodiment thereof, will be more fully understood from the following description and drawings.

BRIEF DESCRIPTION OF SEVERAL VIEWS OF THE DRAWINGS

FIG. 1 is a plan view of an exemplary lead frame for a semiconductor device, in accordance with a representative embodiment of the present invention.

FIG. 2 is a cross-sectional view of an exemplary lead frame for a semiconductor device that may correspond to, for example, the lead frame shown in FIG. 1, in accordance with a representative embodiment of the present invention.

FIG. 3 is a cross-sectional view of an exemplary lead frame for a semiconductor device, in accordance with another representative embodiment of the present invention.

FIG. 4 is a cross-sectional view of an exemplary lead frame for a semiconductor device, in accordance with another representative embodiment of the present invention.

FIG. 5 is a cross-sectional view of an exemplary lead frame for a semiconductor device, in accordance with yet another representative embodiment of the present invention.

FIG. 6 is a cross-sectional view of an exemplary lead frame for a semiconductor device, in accordance with still another representative embodiment of the present invention.

DETAILED DESCRIPTION OF THE INVENTION

Aspects of the present invention relate to lead frames used in assembly and packaging of integrated circuits. More specifically, representative embodiments of the present invention may relate to the preparation of leads frames using strike plating and a self assembly monolayer material to more effectively prevent oxidation of a base layer of the lead frame, while simplifying the manufacturing process, thus reducing manufacturing cost and reducing failure rate.

FIG. 1 is a plan view of an exemplary lead frame **100** for a semiconductor device, in accordance with a representative embodiment of the present invention. As illustrated in FIG. 1, the lead frame may be formed of a metal strip using, for example, a mechanical stamping or a chemical etching method. The lead frame **100** serves as an electric lead or path to connect the circuitry of a semiconductor die mounted to one surface of the lead frame to an external circuit. In addition, the lead frame **100** may serve as a frame for physically fixing or mounting a semiconductor device to an external device, where the semiconductor device may include the lead frame **100**, a semiconductor die, one or more conductive wires that electrically connect the lead frame **100** to the circuitry of the semiconductor die, and an encapsulant that encapsulates the lead frame **100** with the semiconductor die and the one or more conductive wires.

As illustrated in the example of FIG. 1, the lead frame **100** includes a die pad **111** having multiple sides and edges, and a plurality of leads **112**, **113**, and **114** positioned adjacent to each other around the die pad **111**. The die pad **111** of FIG. 1 has a substantially rectangular plate shape and has four sides and four edges. The die pad **111** provides for an area or space to which the semiconductor die may be attached. The plurality of leads **112**, **113**, and **114** may be divided into a plurality of tie bars **112**, a plurality of inner leads **113**, and a plurality of outer leads **114**.

As shown in the example of FIG. 1, in one representative embodiment of the present invention, the tie bars **112** extend outwardly from the respective edges of the die pad **111**. That is to say, the tie bars **112** extend from the edges of the die pad **111** outwardly and in imaginary diagonal directions. The tie bars **112** may function to maintain flattening of the lead frame **100**.

The lead frame **100** comprises a plurality of leads, each having an inner lead **113** and a corresponding outer lead **114**. The plurality of inner leads **113** are spaced apart from the die pad **111** and extend outwardly. The plurality of inner leads **113** are arranged to be perpendicular to the sides of the die pad **111**. The plurality of inner leads **113** are exposed to a portion of the semiconductor die.

The plurality of outer leads **114** are arranged to outwardly extend from and be electrically connected to a corresponding one of the plurality of inner leads **113**. The plurality of outer leads **114** are exposed to a side or bottom portion of semiconductor device and are mounted onto the external device using soldering to then be electrically connected to the external device. As shown in the example of FIG. 1, a ring-shaped dam bar **115** may be formed that runs between the neighboring pairs of inner leads **113** and outer leads **114**. The dam bar **115** may be removed from between neighboring pairs of corresponding inner leads **113** and outer leads **114** in the course of manufacturing the semiconductor device using, for example, a sawing process, thereby electrically isolating the inner lead **113** and outer lead **114** of each lead from a neighboring inner lead **113** and outer lead **114**.

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FIG. 2 is a cross-sectional view of an exemplary lead frame 100 for a semiconductor device that may correspond to, for example, the lead frame 100 shown in FIG. 1, in accordance with a representative embodiment of the present invention. As shown in the example of FIG. 2, the lead frame 100 includes a base layer 110 and a first strike plating layer 120. The base layer 110 forms a base of the lead frame 100 and may be flatly formed. In the representative embodiment shown in FIG. 2, the base layer 110 is made of copper (Cu) having high electrical conductivity.

As shown in the representative embodiment illustrated in FIG. 2, the first strike plating layer 120 is formed on the base layer 110. The first strike plating layer 120 prevents the base layer 110, which in the example of FIG. 2 is made of Cu, from being oxidized, thereby facilitating bonding in connecting a conductive wire to the lead frame 100. In the representative embodiment shown in FIG. 2, the first strike plating layer 120 may be formed, for example, by plating at least one selected from gold, silver, and palladium onto one or more selected portions (e.g., a top surface), or the entire surface of the base layer 110 using a strike plating method. That is, in one representative embodiment of the present invention, a gold strike plating layer may be formed onto one or more portions, or the entire surface of the base layer 110, in another representative embodiment of the present invention, a silver strike plating layer may be formed onto one or more portions, or the entire surface of the base layer 110, and in yet another representative embodiment, a palladium strike plating layer may be formed onto one or more portions, or the entire surface of the base layer 110. Details of the general concept of strike plating are known in the art, and are not described here.

A representative embodiment of the present invention simplifies the process and reduces the cost of production of lead frames by forming a strike plating layer such as, for example, the first strike plating layer 120, at a thickness in a range of approximately 20 nm to approximately 100 nm. By using a strike plating layer thickness in the range of approximately 20 nm to approximately 100 nm in accordance with a representative embodiment of the present invention, incomplete coverage of the base layer (e.g., base layer 110) resulting from strike plating thickness less than 20 nm and increased manufacturing cost resulting from a strike plating thickness greater than 100 nm, may be avoided. In comparison to a conventional process in which a plating of, for example, silver, nickel, and palladium, may be sequentially formed to a thickness in a range of approximately 100 nm to approximately 500 nm, where processing steps before and after the plating may be required, and where many types of chemicals may be required, the use of a representative embodiment of the present invention simplifies the plating process and reduces failure rate.

As described above, a lead frame in accordance with a representative embodiment of the present invention, such as the lead frame 100 of FIG. 1 and FIG. 2, includes a base layer 110 made of copper and a first strike plating layer 120 formed on the base layer 110 using a strike plating method, thereby preventing the base layer 110 from being oxidized while also simplifying the manufacturing process and reducing the manufacturing cost, while also reducing the rate of failure. In addition, bonding of conductive wires to the lead frame 100 is facilitated.

FIG. 3 is a cross-sectional view of an exemplary lead frame 200 for a semiconductor device, in accordance with another representative embodiment of the present invention. The lead frame 200 of FIG. 3 is substantially the same as the lead frame 100 shown in FIG. 2, except for cross-sectional

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structure. Accordingly, the following description will focus on differences between the lead frame 200 and the lead frame 100 shown in FIG. 2, in view of the cross-sectional structure of the lead frame 200.

As shown in the illustration of FIG. 3, a lead frame in accordance with a representative embodiment of the present invention, such as the lead frame 200, may include a base layer 110, a first strike plating layer 220, and a second strike plating layer 230. The first strike plating layer 220 is similar to the first strike plating layer 120 shown in FIG. 2. However, the first strike plating layer 220, which may include copper (Cu), may be formed, for example, by partially (e.g., a top surface) or entirely plating at least one selected from gold, silver, and palladium using a strike plating method. Because the first strike plating layer 220 of FIG. 3 is positioned between the base layer 110 and the second strike plating layer 230, the second strike plating layer 230 can prevent the first strike plating layer 220, even when formed of copper (Cu), from being oxidized.

In the representative embodiment of FIG. 3, the second strike plating layer 230 is formed, for example, by partially (e.g., a top surface) or entirely plating at least one selected from gold, silver, and palladium onto the first strike plating layer 220 using a strike plating method. That is, in some representative embodiments of the present invention, a gold strike plating layer may be formed, for example, on one or more portions, or the entire surface of the first strike plating layer 220. In other representative embodiments of the present invention, a silver strike plating layer may be formed, for example, on one or more portions, or the entire surface of the first strike plating layer 220. In yet other representative embodiments of the present invention, a palladium strike plating layer may be formed, for example, on one or more portions, or the entire surface of the first strike plating layer 220.

In the exemplary embodiment of FIG. 3, the second strike plating layer 230 may be made of a different material from the first strike plating layer 220. For example, if the first strike plating layer 220 is made of copper (Cu), the second strike plating layer 230 may be formed of at least one of gold, silver, and palladium. Because the first strike plating layer 220 and the second strike plating layer 230 may be formed of equivalent materials, bondability, electrical conductivity, and mechanical strength are high. In addition, the second strike plating layer 230 may be formed to a thickness in a range of approximately 20 nm to approximately 100 nm using a strike plating method, like the first strike plating layer 220. In a representative embodiment of the present invention, the second strike plating layer 230 may, for example, be partially or entirely over-coated on the first strike plating layer 220, thereby more effectively preventing the base layer 110 from being oxidized.

As described above, a lead frame in accordance with a representative embodiment of the present invention, such as the lead frame 200 of FIG. 3, may include a base layer 110 made of copper, and a first strike plating layer 220 formed on the base layer 110 using a strike plating method, thereby more effectively preventing the base layer 110 from being oxidized while simplifying the manufacturing process and reducing the manufacturing cost, while also reducing a failure rate. In addition, bonding of one or more conductive wires is facilitated.

FIG. 4 is a cross-sectional view of an exemplary lead frame 300 for a semiconductor device, in accordance with another representative embodiment of the present invention. The lead frame 300 of FIG. 4 is substantially the same as the lead frame 200 shown in FIG. 3, except for cross-sectional

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structure. Accordingly, the following description will focus on differences between the lead frame **300** and the lead frame **200** shown in FIG. **3**, in view of the cross-sectional structure of the lead frame **300**.

As illustrated in the example of FIG. **4**, a lead frame in accordance with a representative embodiment of the present invention, such as the lead frame **300**, may include a base layer **110**, a first strike plating layer **220**, and a self assembly monolayer (SAM) **330**. In a representative embodiment of the present invention, the first strike plating layer **220** may be formed onto the base layer **110** using a strike plating method, and the SAM **330** may be formed, for example, onto one or more portions (e.g., a top surface), or the entire surface of the first strike plating layer **220** using a spin coating method. The SAM **330** prevents external foreign matter or moisture from being induced into the first strike plating layer **220**. The SAM **330** may be melted by heat in the course of forming a conductive wire to allow the conductive wire to be bonded to the first strike plating layer **220**. In a representative embodiment of the present invention, the SAM **330** may be made of a material such as, for example, alkanethiol, having a high affinity for gold, silver, or palladium and forming the first strike plating layer **220**.

As described above, the exemplary lead frame **300** of FIG. **4** includes a base layer **110**, which may be made of copper, a first strike plating layer **220** formed onto the base layer **110** using a strike plating method, and a self assembly monolayer **330** formed onto the first strike plating layer **220** using a spin coating method. Such a representative embodiment of the present invention thereby more effectively prevents the base layer **110** from being oxidized while simplifying the manufacturing process and reducing the manufacturing cost, while also reducing a failure rate. In addition, bonding of the conductive wire is facilitated.

FIG. **5** is a cross-sectional view of an exemplary lead frame **400** for a semiconductor device, in accordance with yet another representative embodiment of the present invention. The lead frame **400** of FIG. **5** is substantially the same as the lead frame **100** shown in FIG. **2**, except for cross-sectional structure. Accordingly, the following description will focus on differences between the lead frame **400**, and the lead frame **100** shown in FIG. **2**, in view of the cross-sectional structure of the lead frame **400**.

As shown in FIG. **5**, a lead frame in accordance with a representative embodiment of the present invention, such as the lead frame **400**, may include a base layer **110**, a rough copper layer **420**, and a first strike plating layer **430**. The rough copper layer **420** may have a roughened top surface and may be formed, for example, by plating copper onto one or more portions (e.g., a top surface), or the entire surface of the base layer **110** using a strike plating method. As illustrated in FIG. **5**, the rough copper layer **420** is disposed between the base layer **110** and the first strike plating layer **430** and can prevent a copper material plated on the base layer **110** from being oxidized. In addition, the rough copper layer **420** has a roughened top surface to have a widened contact area with the first strike plating layer **430**, thereby increasing bondability between the rough copper layer **420** and the first strike plating layer **430**. Further, it is possible to prevent external foreign matter or moisture from being induced into the rough copper layer **420**. In the illustrated embodiment of FIG. **5**, a rough copper layer in accordance with a representative embodiment of the present invention, such as the rough copper layer **420**, may be formed, for example, by plating, which is illustrated by way of example, and may also be formed by a micro-etching method.

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The first strike plating layer **430** is similar to the first strike plating layer **120** shown in FIG. **2**. However, the first strike plating layer **430** of the exemplary lead frame **400** of FIG. **5** is plated on the top surface of the rough copper layer **420** using a strike plating method.

As described above, the exemplary lead frame **400** of FIG. **5** includes a base layer **110** made of copper, a rough copper layer **420** plated on the top surface of the base layer **110**, and a first strike plating layer **430** plated on the rough copper layer **420** using a strike plating method, thereby more effectively preventing the base layer **110** from being oxidized while simplifying the manufacturing process and reducing the manufacturing cost while reducing a failure rate and increasing bondability between the rough copper layer **420** and first strike plating layer **430**. The rough copper layer **420** may be formed using a strike plating method.

FIG. **6** is a cross-sectional view of an exemplary lead frame **500** for a semiconductor device, in accordance with still another representative embodiment of the present invention. The lead frame **500** of FIG. **6** is substantially the same as the lead frame **300** of FIG. **4**, except for cross-sectional structure. Accordingly, the following description will focus on differences between the lead frame **500** and the lead frame **300** shown in FIG. **4**, in view of the cross-sectional structure of the lead frame **500**.

As illustrated in the example of FIG. **6**, a lead frame in accordance with a representative embodiment of the present invention, such as the lead frame **500**, may include a base layer **110** and a self assembly monolayer (SAM) **520**. The SAM **520** of FIG. **6** is similar to the SAM **330** shown in FIG. **4**. However, the SAM **520** may, for example, be formed directly onto the base layer **110** using a spin coating method. The SAM **520** prevents external foreign matter or moisture from being induced into the base layer **110**. In the representative embodiment of FIG. **5**, the SAM **520** may be melted by heat in the course of forming a conductive wire to allow the conductive wire to be bonded to the base layer **110**. The SAM **520** may be made of a material such as, for example, alkanethiol, having a high affinity for a material such as, for example, copper, forming the base layer **110**. Because the SAM **520** may be directly formed on the base layer **110** without an intermediate layer, the manufacturing process of the exemplary lead frame **500** can be simplified and the manufacturing cost can be reduced, while also reducing the rate of failure.

As described above, the exemplary lead frame **500** of FIG. **6** may include a base layer **110** that may be made of copper, and the SAM **520** may be formed directly onto the base layer **110** using a spin coating method, thereby more effectively preventing the base layer **110** from being oxidized while simplifying the manufacturing process, reducing the manufacturing cost and reducing a failure rate.

One aspect of an embodiment of the present invention is to provide a lead frame for a semiconductor device, which includes a base layer made of copper, and a strike plating layer or a self assembly monolayer (SAM), thereby preventing oxidation of the base layer while simplifying the manufacturing process, reducing the manufacturing costs, and reducing a failure rate.

According to aspects of the present invention, there is provided a lead frame for a semiconductor device including a die pad and a plurality of leads positioned adjacent to each other around the die pad, the lead frame comprising a base layer made of copper; and a first strike plating layer formed on one or more portions, or the entire surface of the base layer. The first strike plating layer may be formed by plating at least one selected from gold, silver and palladium using

a strike plating method. The lead frame may further include a second strike plating layer formed on one or more portions, or the entire surface of the first strike plating layer.

The first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method, and the second strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using the strike plating method. The second strike plating layer may be made of a different material from the first strike plating layer. Each of the first strike plating layer and the second strike plating layer may have a thickness in a range of 20 nm to 100 nm.

The lead frame may further include a self assembly monolayer (SAM) coated on one or more portions, or the entire surface of the first strike plating layer. The first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method and the self assembly monolayer (SAM) may be formed by depositing alkanethiol using a spin coating method.

The lead frame may further include a rough copper layer disposed between the base layer and the first strike plating layer. The rough copper layer may have a roughened top surface. The first strike plating layer may be formed by plating at least one selected from gold, silver and palladium using a strike plating method.

According to other aspects of the present invention, there is provided a lead frame for a semiconductor device including a die pad and a plurality of leads positioned adjacent to each other around the die pad, the lead frame including a base layer made of copper; and a self assembly monolayer (SAM) coated on one or more portions, or the entire surface of the base layer. The self assembly monolayer (SAM) may be formed by depositing alkanethiol using a spin coating method.

Aspects of the present invention may also be seen in a lead frame for a semiconductor device, in which the lead frame comprises a die pad and a plurality of leads positioned adjacent to each other around the die pad. The lead frame may comprise a base layer made of copper and a first strike plating layer formed on one or more portions, or the entire surface of the base layer. The first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method, and the first strike plating layer may have a thickness in a range of 20 nm to 100 nm. The lead frame may further comprise a second strike plating layer formed on one or more portions, or the entire surface of the first strike plating layer, and the first strike plating layer and the second strike plating layer may each have a thickness in a range of 20 nm to 100 nm. The first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method, and the second strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using the strike plating method. The second strike plating layer may be made of a different material from the first strike plating layer.

In some representative embodiments, the lead frame may comprise a self assembly monolayer (SAM) coated on one or more portions, or the entire surface of the first strike plating layer. The first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method, and the self assembly monolayer (SAM) may be formed by depositing alkanethiol using a spin coating method. In some representative embodiments, the lead frame may further comprise a rough copper layer disposed between the base layer and the first strike plating

layer, and the rough copper layer may have a roughened top surface. In such embodiments, the first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method.

Additional aspects of the present invention may be observed in a lead frame for a semiconductor device, in which the lead frame comprises a die pad and a plurality of leads positioned adjacent to each other around the die pad. The die pad and the plurality of leads may comprise a base layer made of copper, and a self assembly monolayer (SAM) may be coated on one or more portions, or the entire surface of the base layer. The self assembly monolayer (SAM) may be formed by depositing alkanethiol using a spin coating method.

Further aspects of the present invention may be found in a method of producing a lead frame for a semiconductor device. Such a method may comprise forming a lead frame comprising a die pad and a plurality of leads positioned adjacent to each other around the die pad from a base layer made of copper, and forming a first strike plating layer on one or more portions, or the entire surface of the base layer. Forming the first strike plating layer may comprise plating at least one selected from gold, silver, and palladium using a strike plating method. The method may also comprise forming a second strike plating layer on one or more portions, or the entire surface of the first strike plating layer. Each of the first strike plating layer and the second strike plating layer may have a thickness in a range of 20 nm to 100 nm. The first strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using a strike plating method, the second strike plating layer may be formed by plating at least one selected from gold, silver, and palladium using the strike plating method, and the second strike plating layer may be made of a different material from the first strike plating layer. In some representative embodiments, the first strike plating layer may have a thickness in a range of 20 nm to 100 nm, and the method may comprise forming a self assembly monolayer (SAM) coated on one or more portions, or the entire surface of the first strike plating layer.

As described above, because a lead frame for a semiconductor device in accordance with a representative embodiment of the present invention may include a base layer made of copper and a strike plating layer or a self assembly monolayer (SAM), oxidation of the base layer can be prevented while simplifying the manufacturing process, reducing the manufacturing cost, and reducing a failure rate.

While the present invention has been described with reference to certain embodiments, it will be understood by those skilled in the art that various changes may be made and equivalents may be substituted without departing from the scope of the present invention. In addition, many modifications may be made to adapt a particular situation or material to the teachings of the present invention without departing from its scope. Therefore, it is intended that the present invention not be limited to the particular embodiment disclosed, but that the present invention will include all embodiments falling within the scope of the appended claims.

What is claimed is:

1. A lead frame for a semiconductor device, the lead frame comprising:
 - a die pad;
 - a plurality of leads positioned adjacent to each other around the die pad;
 - a base layer made of copper; and

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a first strike plating layer formed directly on one or more portions of the surface of the base layer, wherein the first strike plating layer has a thickness in a range of 20 nm to 100 nm.

2. The lead frame of claim 1, wherein the first strike plating layer is formed by plating one or more of gold, silver, and palladium using a strike plating method.

3. The lead frame of claim 1, further comprising a second strike plating layer formed on one or more portions of the surface of the first strike plating layer.

4. The lead frame of claim 3, wherein the first strike plating layer and the second strike plating layer each has a thickness in a range of 20 nm to 100 nm.

5. The lead frame of claim 3, wherein the first strike plating layer is formed by plating one or more of gold, silver, and palladium using a strike plating method, and the second strike plating layer is formed by plating one or more of gold, silver, and palladium using the strike plating method.

6. The lead frame of claim 5, wherein the second strike plating layer is made of a different material from the first strike plating layer.

7. The lead frame of claim 1, further comprising a self assembly monolayer (SAM) coated on one or more portions of the surface of the first strike plating layer.

8. The lead frame of claim 7, wherein the first strike plating layer is formed by plating one or more of gold, silver and palladium using a strike plating method and the self assembly monolayer (SAM) is formed by depositing alkanethiol using a spin coating method.

9. A method of producing a lead frame for a semiconductor device, the method comprising:

forming a lead frame comprising a die pad and a plurality of leads positioned adjacent to each other around the die pad from a base layer made of copper;

forming a first strike plating layer directly on one or more portions of the surface of the base layer; and

forming a second strike plating layer on one or more portions of the surface of the first strike plating layer.

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10. The method of claim 9, wherein forming the first strike plating layer comprises plating one or more of gold, silver, and palladium using a strike plating method.

11. The method of claim 9, wherein each of the first strike plating layer and the second strike plating layer has a thickness in a range of 20 nm to 100 nm.

12. The method of claim 9, wherein the first strike plating layer is formed by plating one or more of gold, silver, and palladium using a strike plating method, the second strike plating layer is formed by plating one or more of gold, silver, and palladium using the strike plating method, and the second strike plating layer is made of a different material from the first strike plating layer.

13. The method of claim 9, wherein the first strike plating layer has a thickness in a range of 20 nm to 100 nm, and wherein the method further comprises forming a self assembly monolayer (SAM) coated on one or more portions of the surface of the first strike plating layer.

14. A lead frame for a semiconductor device, the lead frame comprising:

a die pad; and

a plurality of leads positioned adjacent to each other around the die pad;

wherein the lead frame comprises:

a base layer made of copper,

a first strike plating layer formed directly on one or more portions of the surface of the base layer, and

a second strike plating layer formed on one or more portions of the surface of the first strike plating layer.

15. A method of producing a lead frame for a semiconductor device, the method comprising:

forming a lead frame comprising a die pad and a plurality of leads positioned adjacent to each other around the die pad from a base layer made of copper;

forming a first strike plating layer directly on one or more portions of the surface of the base layer; and

wherein the first strike plating layer has a thickness in a range of 20 nm to 100 nm.

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